


Search Notes 	Application/Control No. 10525696	Applicant(s)/Patent Under Reexamination CRUZ ET AL.
	Examiner ALLAHYAR KASRAIAN	Art Unit 2617

SEARCHED			
Class	Subclass	Date	Examiner
370	318	9/15/2008	AK

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Image and keyword search in USPTO, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	9/22/2008	AK
Inventor name and Assignee search in PALM ExPo and EAST	9/8/2008	AK
(370/318,317,395.4.ccls. 455/522,67.11,13.4,453,500,501,513,127.1.ccls.) and ((measur\$3 with (SNR SIR SINR "signal to noise" "signal to interference")) same (data adj2 rate)) and (@ad<="20020905" @rlad<="20020905")	9/8/2008	AK
IEEE Xplore: http://ieeexplore.ieee.org/Xplore/DynWel.jsp	9/8/2008	AK
Google: http://www.google.com	9/8/2008	AK
EPO Data base: http://ep.espacenet.com	9/8/2008	AK
Constulated with Rafael Pérez-Gutiérrez	9/8/2008	AK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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